



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 291795US2PCT		SERIAL NO. 10/580,822	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Janick BIGARRE, et al.			
				FILING DATE May 26, 2006		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/MLB/	AV	BIGARRE J. et al., "TRAPPING OF ELECTRICAL CHARGES AND LASER DAMAGE", PROCEEDINGS OF SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 4932, pages 258-267, XP002289327, 2003					
/MLB/	AW	KOZLOWSKI M. R. et al., "LUMINESCENCE INVESTIGATION OF SiO2 SURFACES DAMAGED BY 0.35 mm LASER ILLUMINATION", SPIE, vol. 3902, pages 138-144, XP002289328, 2000					
/MLB/	AX	GOLDBERG M. et al., "DOSE EFFECTS OF CATHODOLUMINESCENCE IN SiO2 LAYERS ON Si", MATERIALS SCIENCE AND ENGINEERING, vol. B42, pages 293-296, XP002289329, 1996					
/MLB/	AY	STEVENS KALCEFF M. A., "CATHODOLUMINESCENCE MICROCHARACTERIZATION OF THE DEFECT STRUCTURE OF IRRADIATED HYDRATED AND ANHYDROUS FUSED SILICON DIOXIDE", PHYSICAL REVIEW B, vol. 57, pages 5674-5683, XP002289330, 1998					
/MLB/	AZ	REICHLING M., "NANOSECOND UV LASER PULSE INTERACTIONS WITH DIELECTRIC SINGLE CRYSTALS", PROCEEDINGS OF THE SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 3274, pages 2-9, XP002289331, 1998					
						<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Manuel L. Barbee/				Date Considered 09/29/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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